

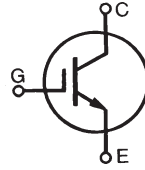
**900V XPT™ IGBTs**  
**GenX3™**
**IXYY8N90C3**  
**IXYP8N90C3**

$$V_{CES} = 900V$$

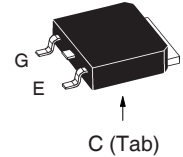
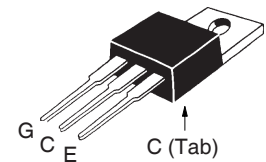
$$I_{C110} = 8A$$

$$V_{CE(sat)} \leq 2.5V$$

$$t_{fi(typ)} = 130ns$$

 High-Speed IGBT  
 for 20-50 kHz Switching


Symbol	Test Conditions	Maximum Ratings	
$V_{CES}$	$T_J = 25^\circ C$ to $175^\circ C$	900	V
$V_{CGR}$	$T_J = 25^\circ C$ to $175^\circ C$ , $R_{GE} = 1M\Omega$	900	V
$V_{GES}$	Continuous	$\pm 20$	V
$V_{GEM}$	Transient	$\pm 30$	V
$I_{C25}$	$T_C = 25^\circ C$	20	A
$I_{C110}$	$T_C = 110^\circ C$	8	A
$I_{CM}$	$T_C = 25^\circ C$ , 1ms	48	A
$I_A$	$T_C = 25^\circ C$	4	A
$E_{AS}$	$T_C = 25^\circ C$	15	mJ
<b>SSOA</b> <b>(RBSOA)</b>	$V_{GE} = 15V$ , $T_{VJ} = 150^\circ C$ , $R_G = 30\Omega$ Clamped Inductive Load	$I_{CM} = 16$ @ $V_{CE} \leq V_{CES}$	A
$P_C$	$T_C = 25^\circ C$	120	W
$T_J$		-55 ... +175	$^\circ C$
$T_{JM}$		175	$^\circ C$
$T_{stg}$		-55 ... +175	$^\circ C$
$T_L$	Maximum Lead Temperature for Soldering	300	$^\circ C$
$T_{SOLD}$	1.6 mm (0.062in.) from Case for 10s	260	$^\circ C$
$M_d$	Mounting Torque (TO-220)	1.13/10	Nm/lb.in.
<b>Weight</b>	TO-252	0.35	g
	TO-220	3.00	g

**TO-252 (IXYY)**

**TO-220 (IXYP)**


G = Gate      C = Collector  
 E = Emitter      Tab = Collector

**Features**

- Optimized for Low Switching Losses
- Square RBSOA
- Positive Thermal Coefficient of  $V_{ce(sat)}$
- Avalanche Rated
- International Standard Package

**Advantages**

- High Power Density
- Low Gate Drive Requirement

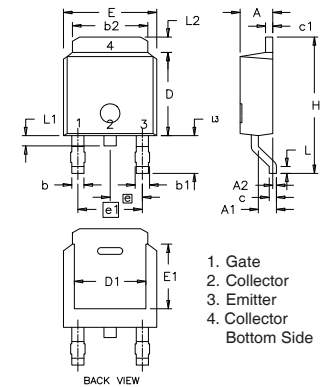
**Applications**

- High Frequency Power Inverters
- UPS
- Motor Drives
- SMPS
- PFC Circuits
- Battery Chargers
- Welding Machines
- Lamp Ballasts

Symbol	Test Conditions ( $T_J = 25^\circ C$ , Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
$BV_{CES}$	$I_C = 250\mu A$ , $V_{GE} = 0V$	950		V
$V_{GE(th)}$	$I_C = 250\mu A$ , $V_{CE} = V_{GE}$	3.5		6.0 V
$I_{CES}$	$V_{CE} = V_{CES}$ , $V_{GE} = 0V$ $T_J = 150^\circ C$			60 $\mu A$ 400 $\mu A$
$I_{GES}$	$V_{CE} = 0V$ , $V_{GE} = \pm 20V$			$\pm 100$ nA
$V_{CE(sat)}$	$I_C = 8A$ , $V_{GE} = 15V$ , Note 1 $T_J = 150^\circ C$	2.15 2.75		2.50 V V

Symbol Test Conditions		Characteristic Values		
(T <sub>J</sub> = 25°C Unless Otherwise Specified)		Min.	Typ.	Max.
g <sub>fs</sub>	I <sub>C</sub> = 8A, V <sub>CE</sub> = 10V, Note 1	2.9	4.8	S
C <sub>ies</sub>	V <sub>CE</sub> = 25V, V <sub>GE</sub> = 0V, f = 1MHz		400	pF
C <sub>oes</sub>			24	pF
C <sub>res</sub>			7.8	pF
Q <sub>g(on)</sub>	I <sub>C</sub> = 8A, V <sub>GE</sub> = 15V, V <sub>CE</sub> = 0.5 • V <sub>CES</sub>		13.3	nC
Q <sub>ge</sub>			3.4	nC
Q <sub>gc</sub>			5.8	nC
t <sub>d(on)</sub>	Inductive load, T <sub>J</sub> = 25°C		16	ns
t <sub>ri</sub>			20	ns
E <sub>on</sub>		I <sub>C</sub> = 8A, V <sub>GE</sub> = 15V	0.46	mJ
t <sub>d(off)</sub>		V <sub>CE</sub> = 0.5 • V <sub>CES</sub> , R <sub>G</sub> = 30Ω	40	ns
t <sub>fi</sub>		Note 2	130	ns
E <sub>off</sub>		0.18	0.50	mJ
t <sub>d(on)</sub>	Inductive load, T <sub>J</sub> = 125°C		17	ns
t <sub>ri</sub>			22	ns
E <sub>on</sub>		I <sub>C</sub> = 8A, V <sub>GE</sub> = 15V	1.00	mJ
t <sub>d(off)</sub>		V <sub>CE</sub> = 0.5 • V <sub>CES</sub> , R <sub>G</sub> = 30Ω	75	ns
t <sub>fi</sub>		Note 2	163	ns
E <sub>off</sub>		0.22	0.50	mJ
R <sub>thJC</sub>				1.20 °C/W
R <sub>thCS</sub>	TO-252	0.35		°C/W
	TO-220	0.50		°C/W

### TO-252 AA Outline



Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	2.19	2.38	0.086	0.094
A1	0.89	1.14	0.035	0.045
A2	0	0.13	0	0.005
b	0.64	0.89	0.025	0.035
b1	0.76	1.14	0.030	0.045
b2	5.21	5.46	0.205	0.215
c	0.46	0.58	0.018	0.023
c1	0.46	0.58	0.018	0.023
D	5.97	6.22	0.235	0.245
D1	4.32	5.21	0.170	0.205
E	6.35	6.73	0.250	0.265
E1	4.32	5.21	0.170	0.205
e	2.28 BSC		0.090 BSC	
e1	4.57 BSC		0.180 BSC	
H	9.40	10.42	0.370	0.410
L	0.51	1.02	0.020	0.040
L1	0.64	1.02	0.025	0.040
L2	0.89	1.27	0.035	0.050
L3	2.54	2.92	0.100	0.115

### Reverse Diode (FRED)

Symbol Test Conditions		Characteristic Value		
(T <sub>J</sub> = 25°C, Unless Otherwise Specified)		Min.	Typ.	Max.
V <sub>F</sub>	I <sub>F</sub> = 10A, V <sub>GE</sub> = 0V, Note 1			3.0 V
				T <sub>J</sub> = 150°C 2.0 V
I <sub>RM</sub>	I <sub>F</sub> = 10A, V <sub>GE</sub> = 0V, -di <sub>F</sub> /dt = 200A/μs, V <sub>R</sub> = 600V		7.5	A
t <sub>rr</sub>		T <sub>J</sub> = 100°C		114
R <sub>thJC</sub>				2.5 °C/W

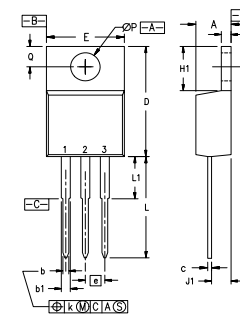
#### Notes:

1. Pulse test, t ≤ 300μs, duty cycle, d ≤ 2%.
2. Switching times & energy losses may increase for higher V<sub>CE</sub> (clamp), T<sub>J</sub> or R<sub>G</sub>.

### ADVANCE TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from a subjective evaluation of the design, based upon prior knowledge and experience, and constitute a "considered reflection" of the anticipated result. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

### TO-220 Outline



Pins: 1 - Gate 2 - Collector  
3 - Emitter

SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.170	.190	4.32	4.83
b	.025	.040	0.64	1.02
b1	.045	.065	1.15	1.65
c	.014	.022	0.35	0.56
D	.580	.630	14.73	16.00
E	.390	.420	9.91	10.66
e	.100 BSC		2.54 BSC	
F	.045	.055	1.14	1.40
H1	.230	.270	5.85	6.85
J1	.090	.110	2.29	2.79
k	0	.015	0	0.38
L	.500	.550	12.70	13.97
L1	.110	.230	2.79	5.84
ØP	.139	.161	3.53	4.08
Q	.100	.125	2.54	3.18

### IXYS Reserves the Right to Change Limits, Test Conditions, and Dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents:	4,835,592	4,931,844	5,049,961	5,237,481	6,162,665	6,404,065 B1	6,683,344	6,727,585	7,005,734 B2	7,157,338B2
	4,850,072	5,017,508	5,063,307	5,381,025	6,259,123 B1	6,534,343	6,710,405 B2	6,759,692	7,063,975 B2	
	4,881,106	5,034,796	5,187,117	5,486,715	6,306,728 B1	6,583,505	6,710,463	6,771,478 B2	7,071,537	

Fig. 1. Output Characteristics @  $T_J = 25^\circ\text{C}$

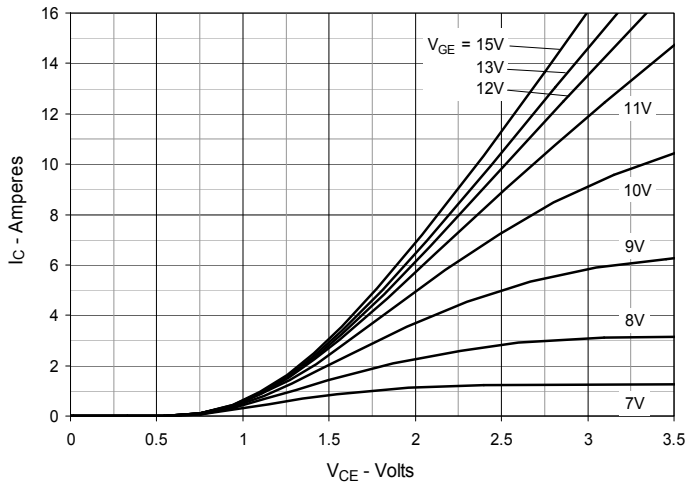


Fig. 2. Extended Output Characteristics @  $T_J = 25^\circ\text{C}$

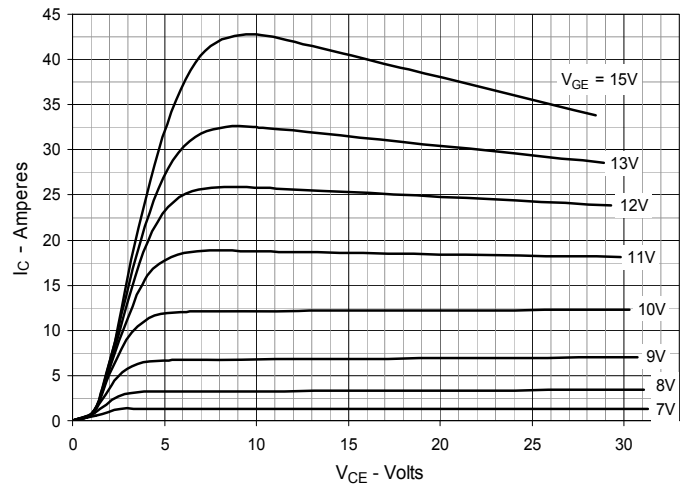


Fig. 3. Output Characteristics @  $T_J = 150^\circ\text{C}$

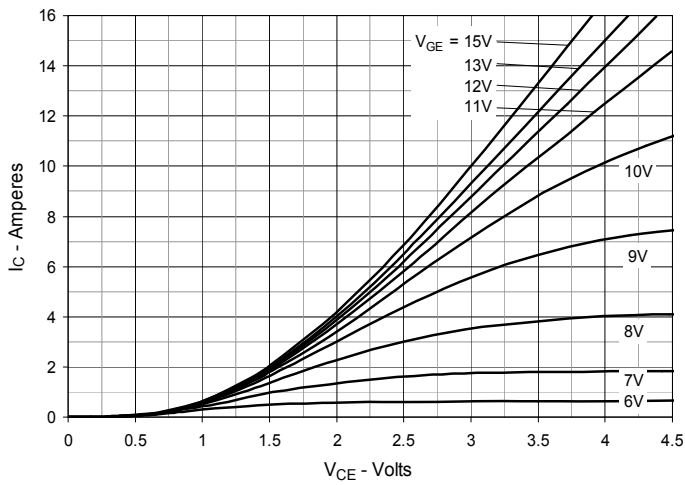


Fig. 4. Dependence of  $V_{CE(sat)}$  on Junction Temperature

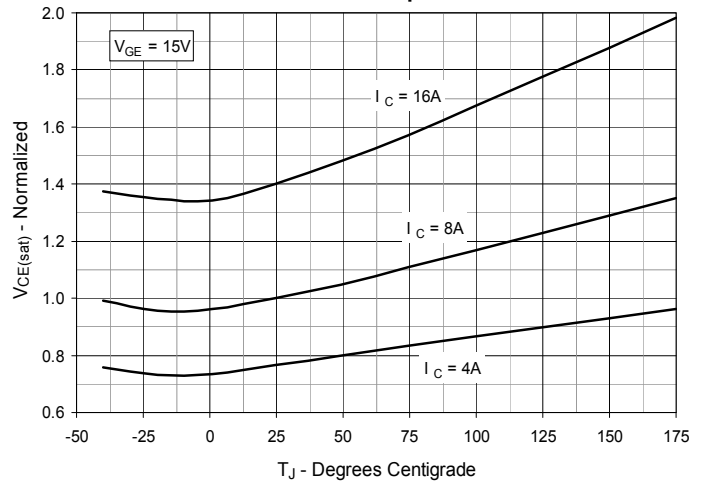


Fig. 5. Collector-to-Emitter Voltage vs. Gate-to-Emitter Voltage

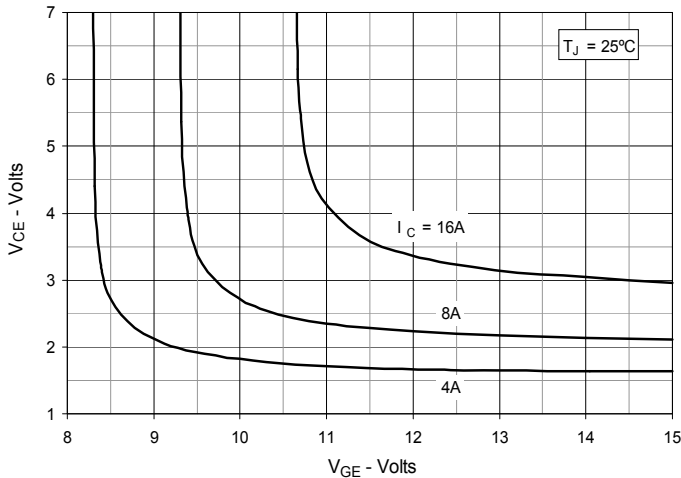


Fig. 6. Input Admittance

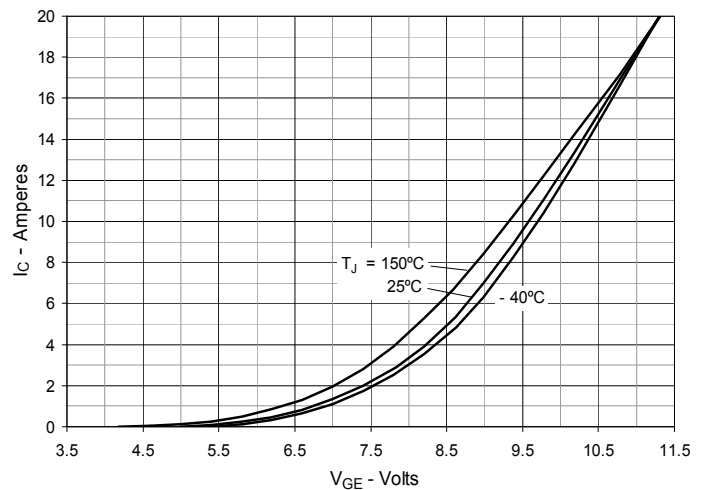


Fig. 7. Transconductance

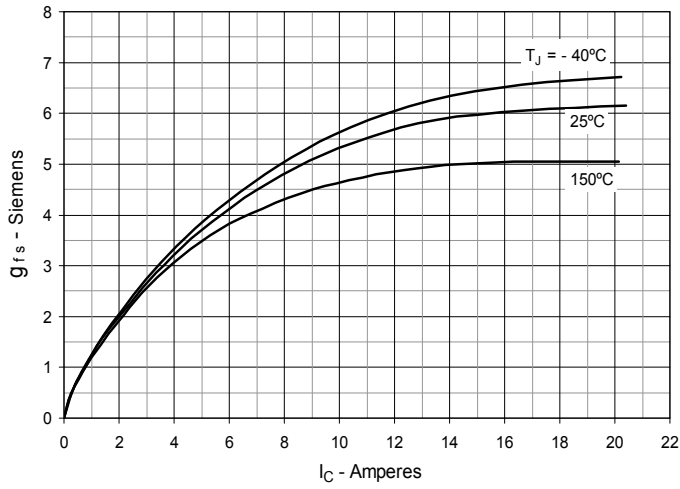


Fig. 8. Gate Charge

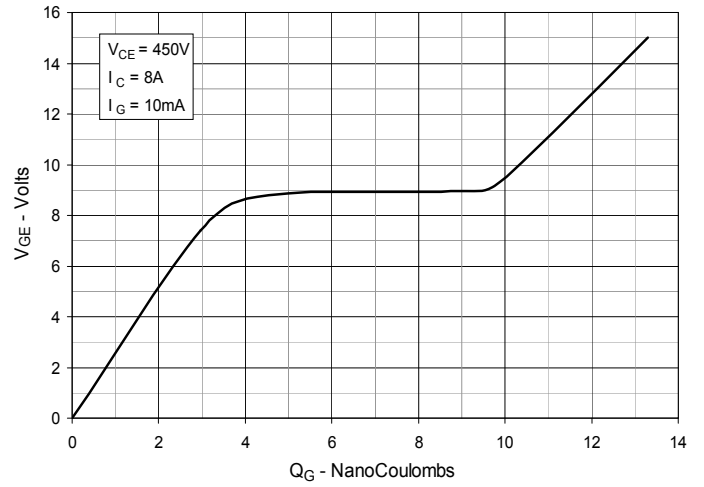


Fig. 9. Capacitance

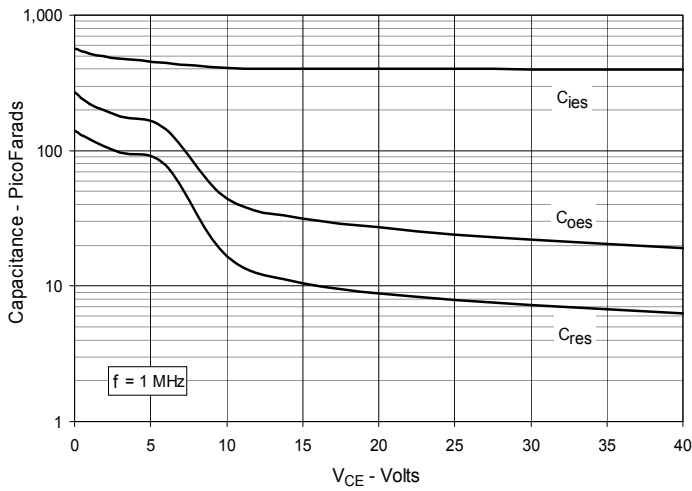


Fig. 10. Reverse-Bias Safe Operating Area

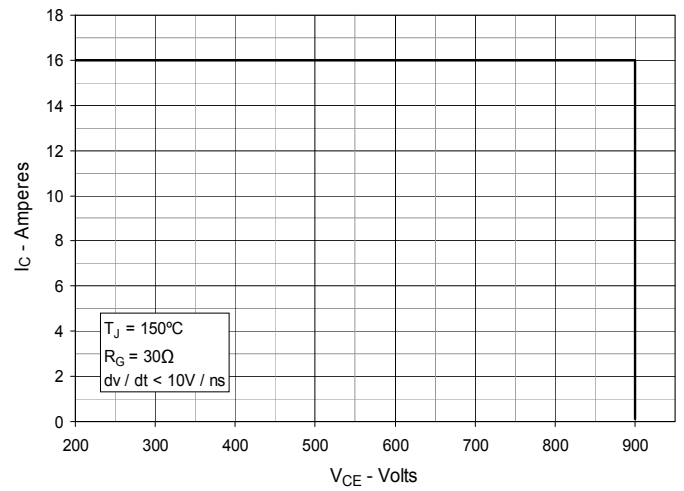
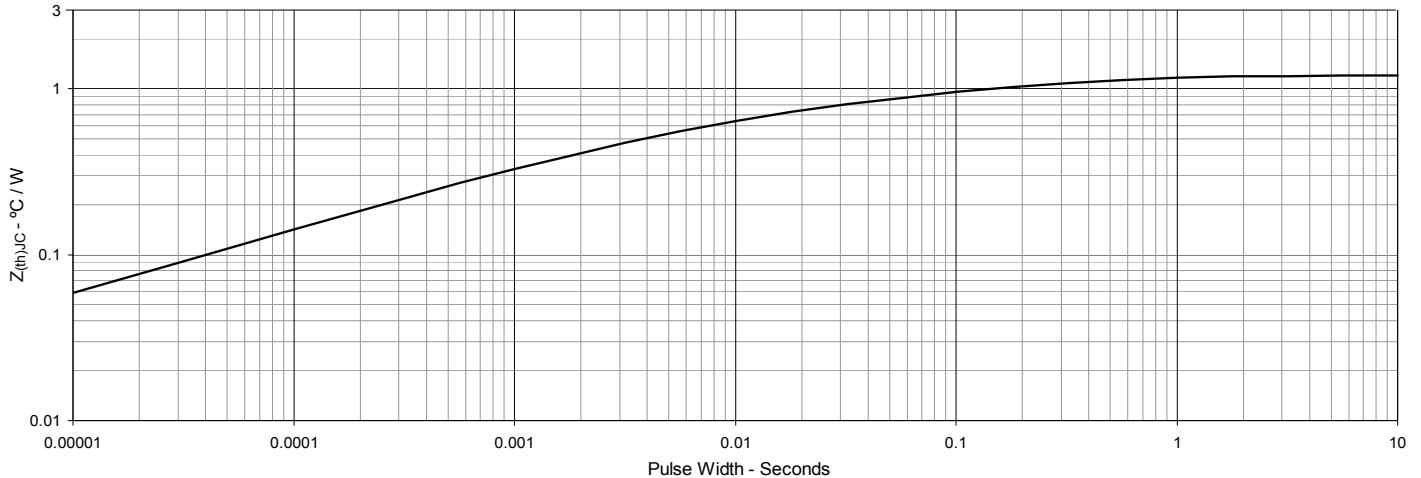
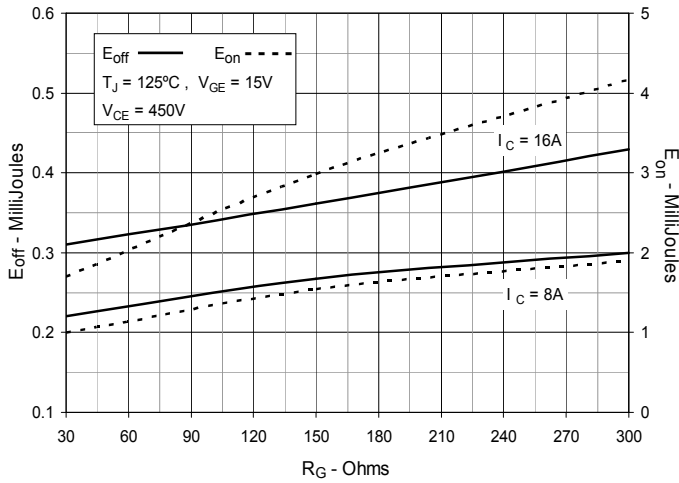


Fig. 11. Maximum Transient Thermal Impedance

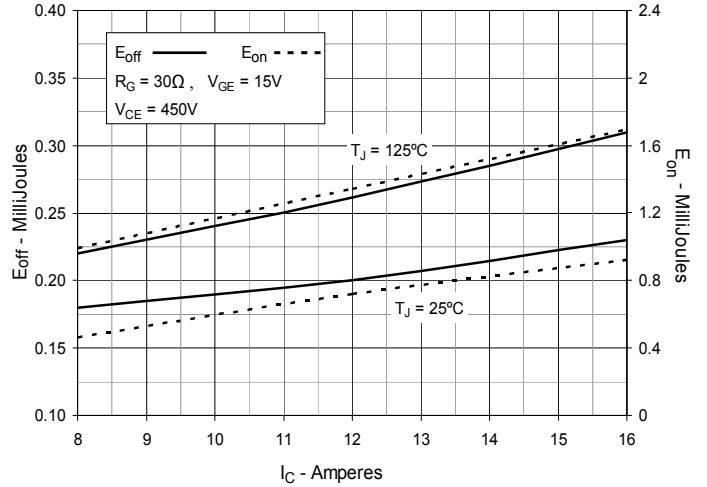


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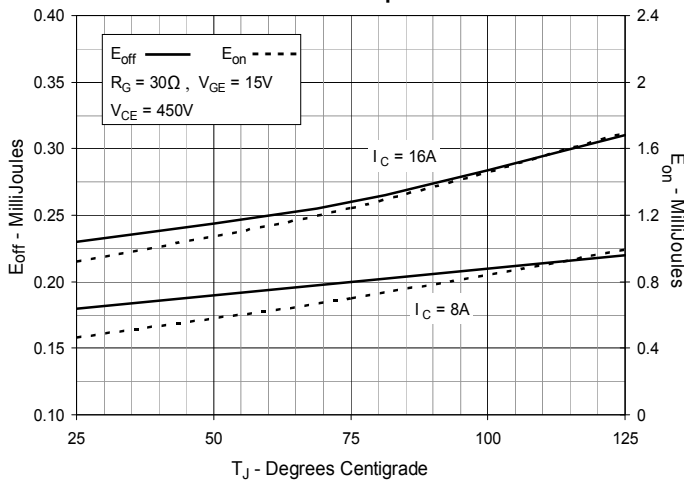
**Fig. 12. Inductive Switching Energy Loss vs. Gate Resistance**



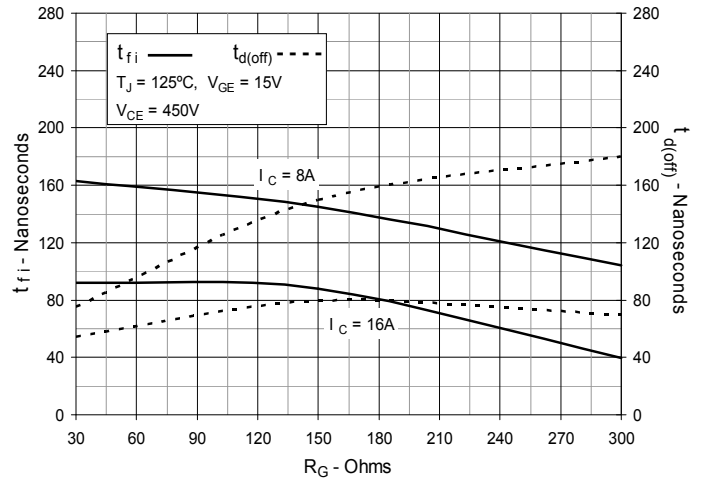
**Fig. 13. Inductive Switching Energy Loss vs. Collector Current**



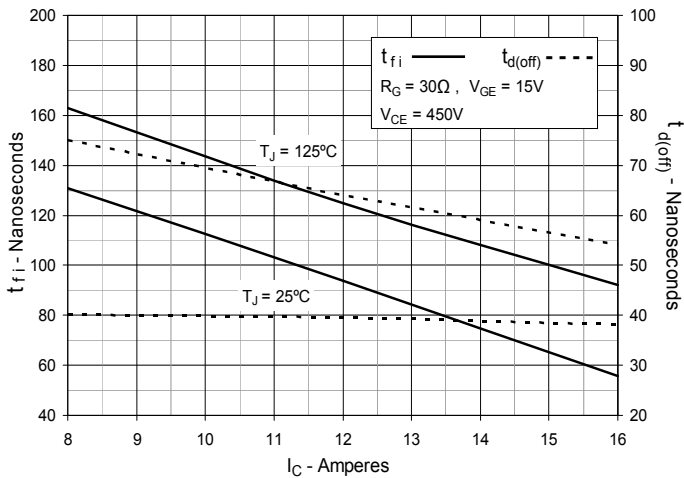
**Fig. 14. Inductive Switching Energy Loss vs. Junction Temperature**



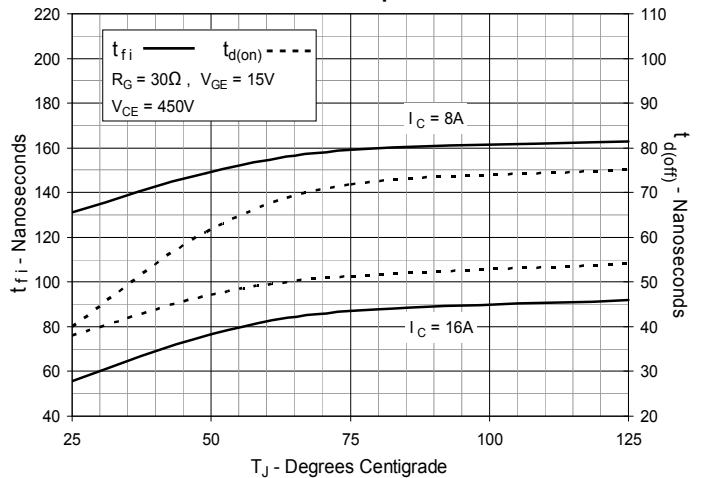
**Fig. 15. Inductive Turn-off Switching Times vs. Gate Resistance**



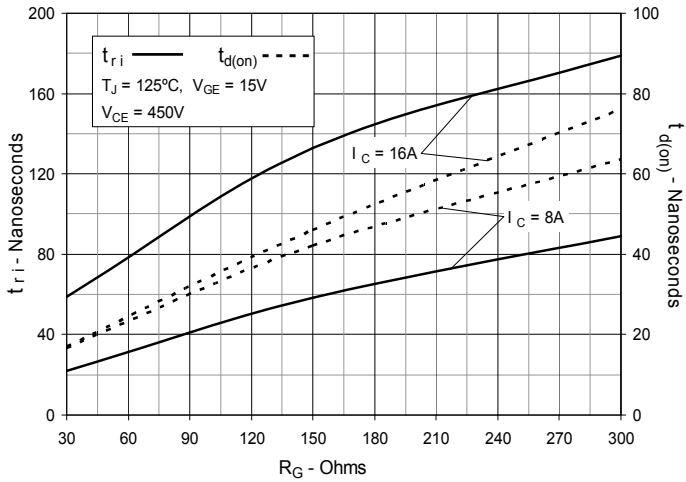
**Fig. 16. Inductive Turn-off Switching Times vs. Collector Current**



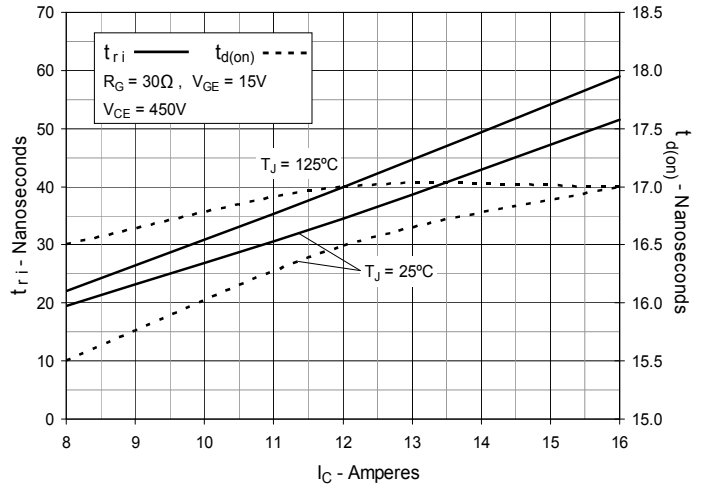
**Fig. 17. Inductive Turn-off Switching Times vs. Junction Temperature**



**Fig. 18. Inductive Turn-on Switching Times vs. Gate Resistance**



**Fig. 19. Inductive Turn-on Switching Times vs. Collector Current**



**Fig. 20. Inductive Turn-on Switching Times vs. Junction Temperature**

